

**Search Notes**

Application/Control No.

10/616,492

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

LEE, YAO-SHENG

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
216	58	2/28/2006	BT
216	63	2/28/2006	BT
216	68	2/28/2006	BT
216	74	2/28/2006	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	2/28/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner